

600V Super-Junction Power MOSFET

DESCRIPTION

600V super-junction Power MOSFET

Super-junction power MOSFET is a revolutionary technology for high voltage power MOSFETs, designed according to the SJ principle. The SJ MOSFET is a price-performance optimized product enabling to target cost sensitive applications in Consumer and Lighting markets, designed by Wuxi Unigroup Microelectronics Company.

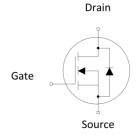
FEATURES

- Very low FOM $R_{DS(on)} \times Q_g$
- 100% avalanche tested
- RoHS compliant

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)







Device Marking and Package Information

Device	Package	Marking
TPU60R330M	TO-251	60R330M

Key Performance Parameters

Parameter	Value	Unit
V _{DS} @ T _{j,max}	600	V
R _{DS(on),max}	0.33	Ω
I _D	11	A
$Q_{g,typ}$	19	nC
I _{DM}	33	A



Absolute Maximum Ratings $T_C = 25^{\circ}C$, unless otherwise noted				
Parameter		Symbol	Value	Unit
Drain-Source Voltage (V _{GS} = 0V)		V _{DSS}	600	V
Continuous Drain Current	$T_{\rm C} = 25^{\rm o}{\rm C}$		11	A
Continuous Brain Garrent	TC = 100°C	l _D	6.6	
Pulsed Drain Current	(note1)	I _{DM}	33	А
Gate-Source Voltage		V_{GSS}	±30	V
Single Pulse Avalanche Energy	(note2)	E _{AS}	210	mJ
Repetitive Avalanche Energy (note2)		E _{AR}	0.32	mJ
Avalanche Current		I _{AR}	1.8	А
MOSFET dv/dt ruggedness, V _{DS} = 0480V		dv/dt	50	V/ns
Power Dissipation		P _D	83	W
Continuous Body Diode Current		I _S	9.4	
Pulsed Diode Forward Current (note1)		I _{SM}	33	A
Reverse diode dv/dt (note3)		dv/dt	15	V/ns
Maximum diode commutation speed (note3)		di _f /dt	500	A/us
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55~+150	°C

Thermal Resistance			
Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	R _{thJC}	1.5	•c/w
Thermal Resistance, Junction-to-Ambient	R _{thJA}	62] "0///



			Value				
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Max. Unit	
Static	•						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0V, I_D = 250\mu A$	600			V	
		$V_{DS} = 600V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1		
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 600V, V_{GS} = 0V, T_{J} = 150^{\circ}C$			50	μΑ	
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 30V$			±100	nA	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.5		4.5	V	
Drain-Source On-Resistance	R _{DS(on)}	$V_{GS} = 10V, I_D = 5.5A$		0.29	0.33	Ω	
Gate resistance	R_{G}	f = 1.0MHz open drain		18		Ω	
Dynamic	-!			!	!		
Input Capacitance	C _{iss}	V 0V		857			
Output Capacitance	C _{oss}	$V_{GS} = 0V,$ $V_{DS} = 100V,$		31		pF	
Reverse Transfer Capacitance	C _{rss}	f = 1.0MHz		1.5			
Total Gate Charge	Q_g			19.0			
Gate-Source Charge	Q_{gs}	$V_{DD} = 480V, I_{D} = 11A, V_{GS} = 10V$		4.8		nC	
Gate-Drain Charge	Q_{gd}	. 65		7.2			
Turn-on Delay Time	t _{d(on)}			28			
Turn-on Rise Time	t _r	$V_{DD} = 400V, I_{D} = 11A,$		61			
Turn-off Delay Time	t _{d(off)}	$R_G = 25\Omega$		89		ns	
Turn-off Fall Time	t _f			41			
Drain-Source Body Diode Characte	ristics						
Body Diode Voltage	V _{SD}	$T_J = 25^{\circ}\text{C}, I_{SD} = 5.5\text{A}, V_{GS} = 0\text{V}$		0.9	1.2	V	
Reverse Recovery Time	t _{rr}			377		ns	
Reverse Recovery Charge	Q _{rr}	$V_R = 400V, I_F = I_S,$ $di_F/dt = 100A/\mu s$		3.4		μC	
Peak Reverse Recovery Current	I _{rrm}			17.8		Α	

Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. I_{AS} = 1.8A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25 $^{\circ}$ C
- 3. Identical low side and high side switch with identical ${\rm R}_{\rm G}$



Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted

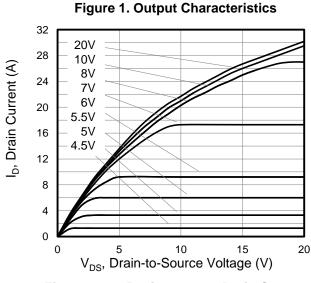


Figure 3. On-Resistance vs. Drain Current

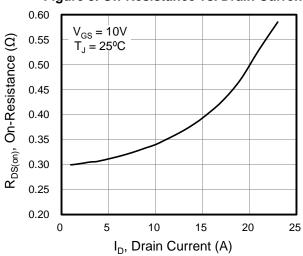


Figure 2. Transfer Characteristics

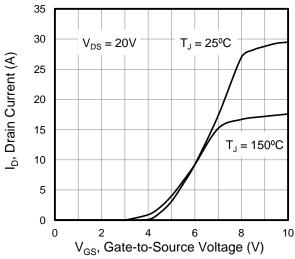


Figure 4. Capacitance

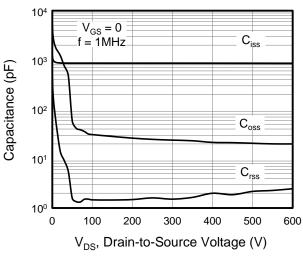
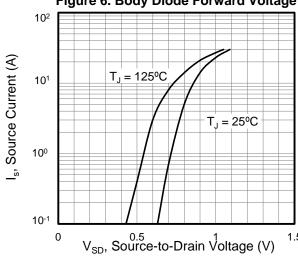


Figure 6. Body Diode Forward Voltage





Typical Characteristics $T_J = 25^{\circ}C$, unless otherwise noted

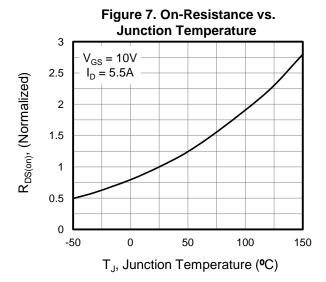


Figure 9. Transient Thermal Impedance TO-251

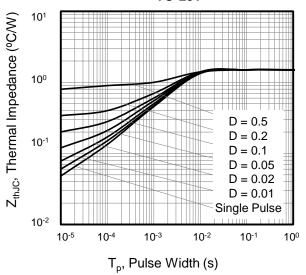


Figure 8. Breakdown voltage vs. Junction Temperature

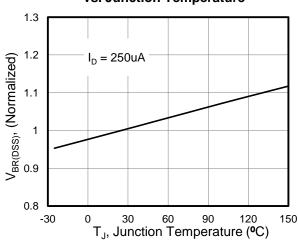
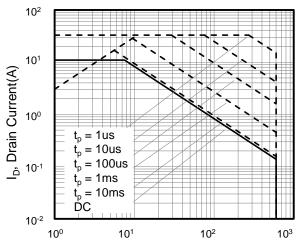


Figure 10. Safe operation area for TO-251



V_{DS}, Drain-Source Voltage(V)



Figure A: Gate Charge Test Circuit and Waveform

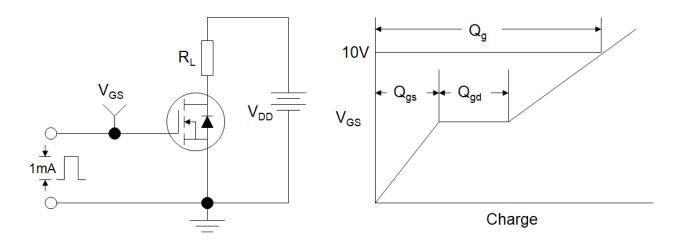


Figure B: Resistive Switching Test Circuit and Waveform

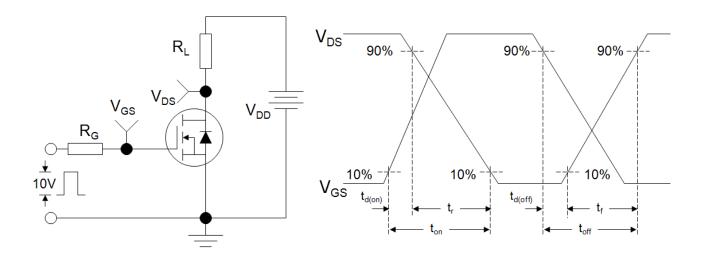
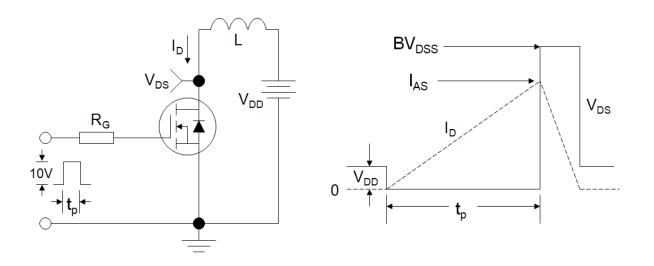
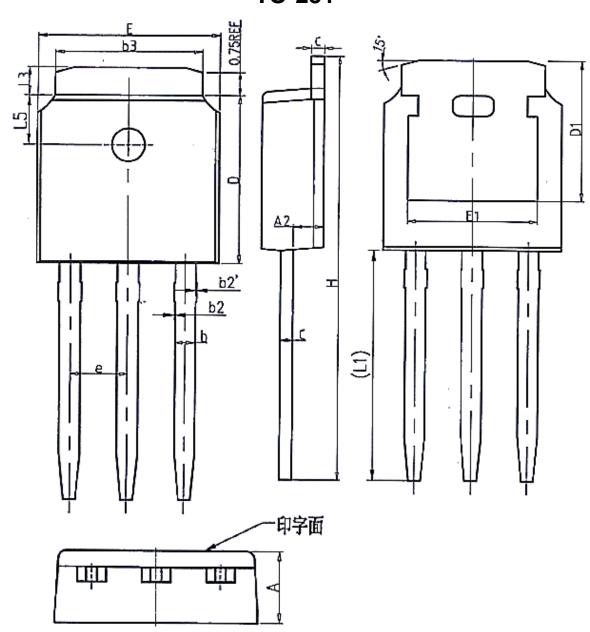


Figure C: Unclamped Inductive Switching Test Circuit and Waveform





TO-251



Unit:mm					
Symbol	Min.	Nom	Max.		
А	2.20	2.30	2.40		
A2	0.97	1.07	1.17		
b	0.68	0.78	0.90		
b2	0.00	0.04	0.10		
b2′	0.00	0.04	0.10		
b3	5.20	5.33	5.50		
С	0.43	0.53	0.63		
D	5.98	6.10	6.22		

Unit:mm				
Symbol	Min.	Nom	Max.	
D1	5.30 REF			
Е	6.40	6.60	6.80	
E1	4.63	-	-	
е	2.286 BSC			
Н	16.22	16.52	16.82	
L1	9.15	9.40	9.65	
L3	0.88	1.02	1.28	
L5	1.65	1.80	1.95	



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